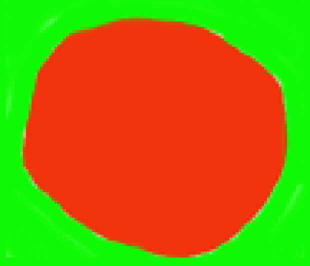

LATW2005

6thIEEE Latin-American**TestWorkshop**

March 30th - April 2nd, 2005
Salvador, Bahia, Brazil

www.latw.net

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Call for Papers

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The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind. The 6th edition of LATW will be held in conjunction with the XI Workshop IBERCHIP, starting March 28th at the same place. The best papers presented at the 6th LATW will be invited to be re-submitted to the IEEE Design and Test of Computers and Journal of Integrated Circuits and Systems.

Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Dependability Estimation
- Design and Synthesis for Testability
- Design Verification/Validation
- E-Beam and Thermal Testing
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation Hardening Techniques
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization

Paper Submission Information:

To encourage and facilitate informal discussion, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions **should be done via the workshop webpage.**

www.latw.net

Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop web page. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Co-Chairs

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Submission deadline:	**November 12th, 2004**
Notification of acceptance:	**December 18th, 2004**
Camera Ready:	**January 17th, 2005**

LATW2005 will be held in Salvador, Brazil. Salvador of Bahia is one of the most beautiful colonial cities in Brazil. You will be surprised by an incredible history, full of magic and charm, as seen at Salvador´s historic district, declared by UNESCO as Treasure of the Humanity. It was the capital of the colonial Brazil, reason why it has such a rich historic and architectural heritage. Glorious tropical beaches surround Salvador and the well-known sounds of the native music may be listened everywhere. Salvador is just 2h20min from São Paulo and 8h30min from Lisbon.

Sponsored by:

IEEE Computer Society Test Technology Technical Council (TTTC)

Organized by:

Universidade Federal do Rio Grande do Sul (UFRGS)
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